

Please type a plus sign (+) inside this box → {+}

PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1993, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO		<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (use as many sheets as necessary)		Application Number	Based on SN 10/035,441
		Filing Date	Filed: January 4, 2002
		First Named Inventor	Naoki YAMAGUCHI et al.
		Group Art Unit	1763
		Examiner Name	Anita Karen Alanko
Sheet 1	of 3	Attorney Docket Number	0756-7191

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.*	U.S. Patent Document		Name of Patent or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code* (if known)		
CL		5,808,318		Masumo et al.	09/15/1998
		5,904,550		Yamaguchi	05/18/1999
		5,773,309		Weiner	06/30/1998
		5,851,860		Makita et al.	12/22/1998
		5,707,882		Hamada et al.	01/13/1998
		5,365,875		Asai et al.	11/22/1994
		5,772,861		Meredith, Jr. et al.	06/30/1998
		5,747,201		Nakayama et al.	05/05/1998
		5,454,347		Shibata et al.	10/03/1995
		4,388,145		Hawkins et al.	06/14/1983
		5,529,630		Imahashi et al.	06/25/1996
		5,147,826		Liu et al.	09/15/1992
		5,275,851		Fonash et al.	01/04/1994
		5,569,610		Zhang et al.	10/29/1996
		4,332,833		Aspnes et al.	06/01/1982
		5,131,752		Yu et al.	07/21/1992
		5,387,309		Bobel et al.	02/07/1995
CL		5,472,545-505		Lee et al.	12/05/1995

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.*	Foreign Patent Document			Name of Patent or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office*	Number*	Kind Code* (if known)			
CL		JP	05-243576			09/21/1993	Abst.
CL		JP	08-051078			02/20/1996	Abst.
CL		JP	06-204132			07/22/1994	Abst.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.*	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T*
CL		F. Ueno "Observation of fast microscopic phase change phenomena of chalcogenide thin films," Japanese Journal of Applied Physics, Supplement, Vol. 26, Supplement 26-4, pp. 55-60, 1987.	
CL		N. Kondo et al., "Film thickness measurement of ultrathin film using light of UV wavelength," Proceedings of the SPIE, Vol. 1673, pp. 392-402, 1992.	

Examiner Signature	<i>calvin</i>	Date Considered	6.20.05
--------------------	---------------	-----------------	---------

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

BEST AVAILABLE COPY